Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/726,834	LEE, CHIOU-HAUN
Examiner	**Art Unit**
Scott E. Jones	3714

SEARCHED			
Class	Subclass	Date	Examiner
463	9, 14	5/28/2007	SEJ
273	153R,156	5/28/2007	SEJ
273	157R,153 S	5/28/2007	SEJ
273	153J	5/28/2007	SEJ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Attached Search History		5/28/2007	SEJ

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text Searched EAST USPAT, USPGPUB, EPO, JPO, and DERWENT databases.	5/28/2007	SEJ